SMD Type Power Inductor

TPRHC1207F-SERIES

		ECN HISTORY	LIST		
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	16/09/13	新發行	楊祥忠	詹偉特	何秦芝
洪			•		•
備					
註					

SMD Type Power Inductor

TPRHC1207F-SERIES

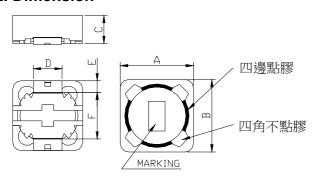
1. Features

- 1. Magnetic Shielded surface mount inductor with high current rating.
- 2.Low resistance to keep power loss minimum.
- 3.100% Lead(Pb) & Halogen-Free and RoHS compliant.





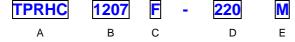
2. Dimension



Series	A(mm)	B(mm)	C(mm)	D(mm)	E(mm)	F(mm)
TPRHC1207F	12.8 max.	12.8 max.	8.5 max.	5.0 ref.	2.2 ref.	7.6 ref.

Units: mm

3. Part Numbering



A: Series (the tin clip)

B: Dimension

C: Lead free type

D: Inductance 220=22.0uH, 2R4=2.4uH, 221=220uH

E: Inductance Tolerance M=±20%, Y=±30%

4. Specification

TAI-TECH Part Number	Inductance (uH)	Tolerance (%)	Test Frequency (Hz)	DCR (Ω) max.	IDC (A) max.
TPRHC 1207F-1R2Y	1.2	± 30%	1V/100K	0.0070	9.80
TPRHC 1207F-2R2Y	2.2	±30%	1V/100K	0.0115	8.00
TPRHC 1207F-2R4Y	2.4	± 30%	1V/100K	0.0115	8.00
TPRHC 1207F-3R3Y	3.3	± 30%	1V/100K	0.0135	12.00
TPRHC 1207F-3R5Y	3.5	± 30%	1V/100K	0.0135	7.50
TPRHC 1207F-4R7Y	4.7	± 30%	1V/100K	0.0158	6.80
TPRHC 1207F-6R1Y	6.1	± 30%	1V/100K	0.0176	6.60
TPRHC 1207F-6R8Y	6.8	±30%	1V/100K	0.0185	6.20
TPRHC 1207F-7R6Y	7.6	± 30%	1V/100K	0.0200	5.90
TPRHC 1207F-100M	10	± 20%	1V/1K	0.0216	5.40
TPRHC 1207F-120M	12	± 20%	1V/1K	0.0243	4.90

-

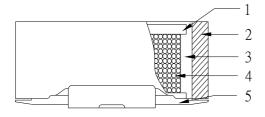
TAI-TECH Part Number	Inductance (uH)	Tolerance (%)	Test Frequency (Hz)	DCR (Ω) max.	IDC (A) max.
TPRHC 1207F-150M	15	± 20%	1V/1K	0.0270	4.50
TPRHC 1207F-180M	18	± 20%	1V/1K	0.0392	3.90
TPRHC 1207F-220M	22	± 20%	1V/1K	0.0432	3.60
TPRHC 1207F-270M	27	± 20%	1V/1K	0.0459	3.40
TPRHC 1207F-330M	33	± 20%	1V/1K	0.0648	3.00
TPRHC 1207F-390M	39	± 20%	1V/1K	0.0729	2.75
TPRHC 1207F-470M	47	± 20%	1V/1K	0.1000	2.50
TPRHC 1207F-560M	56	± 20%	1V/1K	0.1100	2.35
TPRHC 1207F-680M	68	± 20%	1V/1K	0.1400	2.10
TPRHC 1207F-820M	82	± 20%	1V/1K	0.1600	1.95
TPRHC 1207F-101M	100	± 20%	1V/1K	0.2200	1.70
TPRHC 1207F-121M	120	± 20%	1V/1K	0.2500	1.60
TPRHC 1207F-151M	150	± 20%	1V/1K	0.2800	1.42
TPRHC 1207F-181M	180	± 20%	1V/1K	0.3500	1.30
TPRHC 1207F-221M	220	± 20%	1V/1K	0.3900	1.16
TPRHC 1207F-271M	270	± 20%	1V/1K	0.5600	1.06
TPRHC 1207F-331M	330	± 20%	1V/1K	0.6400	0.95
TPRHC 1207F-391M	390	± 20%	1V/1K	0.7000	0.88
TPRHC 1207F-471M	470	± 20%	1V/1K	0.9800	0.79
TPRHC 1207F-561M	560	± 20%	1V/1K	1.0700	0.73
TPRHC 1207F-681M	680	± 20%	1V/1K	1.4600	0.67
TPRHC 1207F-821M	820	± 20%	1V/1K	1.6400	0.60
TPRHC 1207F-102M	1000	± 20%	1V/1K	1.8200	0.55

Note:

Based on inductance change $\ (\ \triangle L/L0 \ : \ \leqq \mbox{-}35\% \) \ @$ ambient temp. 25 $\ensuremath{\circlearrowright}$

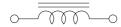
Based on temperature rise $(\triangle T : 40^{\circ}C \text{ typ.})$

5. Material List



No.	Item	Materials
1	Core	Ferrite Core (DR Type)
2	Core	Ferrite Core (RI Type)
3	Glue	Ероху
4	Wire	Copper Wire
5	Clip	The Tin Clip

6. Schematic Diagram

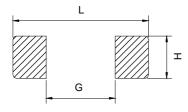


7. Reliability and Test Condition

Performance	Test Condition
-40~+125℃ (Including self - temperature rise)	
-40~+125℃ (on board)	
st	1
	HP4284A,CH11025,CH3302,CH1320,CH1320S
Refer to standard electrical characteristics list.	LCR Meter.
	CH16502, Agilent 33420 A Micro-Ohm Meter.
A1 < 0504	Saturation DC Current (Isat) will cause L0
\(\triangle \L \leq 35\%.\)	to drop △L(%)
	Heat Rated Current (Irms) will cause the coil temperature rise
	$\triangle T(^{\circ}\mathbb{C})$ without core loss.
Approximately △140℃	1.Applied the allowed DC current
	2.Temperature measured by digital surface thermometer
	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles) Temperature: 125±2°C (Inductor)
	Applied current : rated current
	Duration: 1000±12hrs
	Measured at room temperature after placing for 24±2 hrs
1	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles
	Humidity: 85±2%R.H,
	Temperature : 85°C ±2°C
Appearance : No damage.	Duration: 1000hrs Min. with 100% rated current
」 ''	Measured at room temperature after placing for 24±2 hrs
Q : Shall not exceed the specification value.	Preconditioning: Run through IR reflow for 2 times. (IPC/JEDEC J-STD-020DClassification Reflow
RDC: within ±15% of initial value and shall not	Profiles
exceed the specification value	 Baked at50°C for 25hrs, measured at room temperature after placing for 4 hrs.
	2. Raise temperature to 65±2°C 90-100%RH in 2.5hrs, and
	keep 3 hours, cool down to 25°C in 2.5hrs.
	 Raise temperature to 65±2℃ 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25℃ in
	2.5hrs,keep at 25°C for 2 hrs then keep at -10°C for 3 hrs
	4. Keep at 25℃ 80-100%RH for 15min and vibrate at the
	frequency of 10 to 55 Hz to 10 Hz, measure at room temperature after placing for 1~2 hrs.
	-40-+125°C (Including self - temperature rise) -40-+125°C (on board) st Refer to standard electrical characteristics list. △L≤35%. Approximately △T40°C Appearance: No damage. Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not

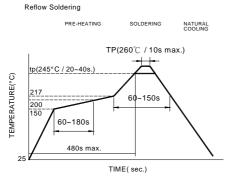
Item	Performance	Test Condition					
Thermal shock Vibration	Appearance : No demage	Preconditioning: Run through IR reflow for 2 times. (IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle Step1: -40±2°C 30±5min Step2: 25±2°C ≤0.5min Step3: 125±2°C 30±5min Number of cycles: 500 Measured at room temperature after placing for 24±2 hrs Oscillation Frequency: 10 ~ 2K ~ 10Hz for 20 minutes Equipment: Vibration checker Total Amplitude:1.52mm±10%					
Shock	Appearance: No damage. Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value	Testing Time : 12 hours(20 minutes, 12 cycles each of 3 orientations). Type					
SHOCK		SMD 50 11 Half-sine 11.3					
		Lead 50 11 Half-sine 11.3					
Bending		Shall be mounted on a FR4 substrate of the following dimensions: >=0805:40x100x1.2mm <0805:40x100x0.8mm Bending depth: >=0805:1.2mm <0805:0.8mm duration of 10 sec.					
Solderability	More than 95% of the terminal electrode should be covered with solder。	Preheat: 150°C,60sec.。 Solder: Sn96.5% Ag3% Cu0.5% Temperature: 245±5°C。 Flux for lead free: Rosin. 9.5%。 Dip time: 4±1sec。 Depth: completely cover the termination					
		Number of heat cycles: 1					
Resistance to Soldering Heat		Temperature (°C) Time(s) Temperature ramp/immersion and emersion rate					
Tied		260 ±5(solder temp) 10 ±1 25mm/s ±6 mm/s					
Terminal Strength	Appearance: No damage. Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles With the component mounted on a PCB with the device to be tested, apply a force (>0805:1kg , <=0805:0.5kg)to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to the component being tested.					

8. Recommended PC Board Pattern



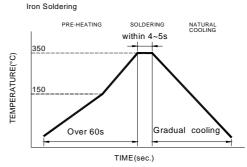
L(mm)	G(mm)	H(mm)
12.6	7.0	5.4

9. Soldering



Reflow times: 3 times max.

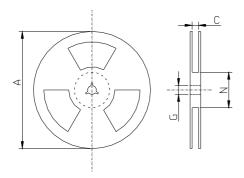
Fig.1



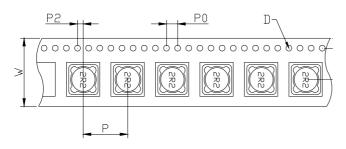
Iron Soldering times: 1 times max.

Fig.2

10. Packaging Information



Style	A(mm)	C(mm)	G(mm)	N(mm)
13"X24mm	330	24.5±0.5	13.5±0.5	100±1



Style	W(mm)	P(mm)	P2(mm)	D(mm)	Po(mm)	Packaging Qty(pcs)
24mm	24±0.3	16±0.1	2±0.1	1.5±0.25	4±0.1	400

Application Notice

· Storage Conditions (component level)

To maintain the solderability of terminal electrodes:

- 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.



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(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件 (泗洪) 有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 / NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI,

TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市篷朗昆嘉高科技工業區郭澤略 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

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(江蘇省宿遗市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD,

SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on

behalf of the applicant as):

樣品名稱(Sample Description)

BASE TYPE CHOKE COIL/ INDUCTOR

樣品型號(Style/Item No.)

TPRH · TPS · TPH · TPL · TPRHC SERIES

收件日期(Sample Receiving Date)

2016/02/26

測試期間(Testing Period)

2016/02/26 TO 2016/03/07

測試結果(Test Results) :

請見下一頁 (Please refer to next pages).



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SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)

測試結果(Test Results)

測試部位(PART NAME)No.1

整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
鎬 / Cadmium (Cd)	mg/kg	参考IEC 62321-5: 2013方法,以感應 耦合電漿原子發射光譜儀檢測./ With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n. d.
鉛 / Lead (Pb)	mg/kg	参考IEC 62321-5: 2013方法, 以感應 耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n. d.
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4: 2013方法,以感應 耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-4: 2013 and performed by ICP-AES.		n. d.
六價絡 / Hexavalent Chromium Cr(VI)	mg/kg	参考IEC 62321: 2008方法,以UV-VIS 檢測. / With reference to IEC 62321: 2008 and performed by UV- VIS.	2	n. d.
六溴環十二烷及所有主要被辨別出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified (α - HBCDD, β - HBCDD, γ - HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	參考IEC 62321: 2008方法,以氣相層 析/質譜儀檢測. / With reference to IEC 62321: 2008 method. Analysis was performed by GC/MS.	5	n. d.



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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result)
鄰苯二甲酸丁苯甲酯 / BBP (Butyl Benzyl phthalate) (CAS No.: 85-68-7)	mg/kg		50	n. d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	mg/kg		50	n. d.
鄰苯二甲酸二 (2-乙基己基)酯 / DEHP (Di- (2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	mg/kg		50	n. d.
鄰苯二甲酸二異丁酯 / DIBP (Di- isobutyl phthalate) (CAS No.: 84-69- 5)	mg/kg	參考IEC 62321-8 (111/321/CD),以氣 相層析儀/質譜儀檢測之. / With reference to IEC 62321-8	50	n. d.
鄰苯二甲酸二異癸酯 / DIDP (Di- isodecyl phthalate) (CAS No.: 26761- 40-0; 68515-49-1)	mg/kg	(111/321/CD). Analysis was performed by GC/MS.	50	n. d.
鄰苯二甲酸二異壬酯 / DINP (Di- isononyl phthalate) (CAS No.: 28553- 12-0; 68515-48-0)	mg/kg		50	n, d.
鄰苯二甲酸二正辛酯 / DNOP (Di-n-octyl phthalate) (CAS No.: 117-84-0)	mg/kg		50	n. d.
鹵素 / Halogen				
鹵素(氟)/ Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg		50	n. d.
鹵素 (氣) / Halogen-Chlorine (C1) (CAS No.: 22537-15-1)	mg/kg	参考BS EN 14582:2007,以離子層析儀 分析. / With reference to BS EN	50	n. d.
鹵素 (溴) / Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg	14582:2007. Analysis was performed by IC.	50	n. d.
鹵素 (碘) / Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg		50	n. d.

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方法偵測 結果 (Result) 測試方法 測試項目 單位 極限值 (Method) (Unit) (Test Items) (MDL) No. 1 多溴聯苯總和 / Sum of PBBs n. d. mg/kg -溴聯苯 / Monobromobiphenyl 5 n.d. mg/kg 5 mg/kg n. d. 5 三溴聯苯 / Tribromobiphenyl n, d. mg/kg 5 mg/kg n. d. 四溴聯苯 / Tetrabromobiphenyl 5 n. d. 五溴聯苯 / Pentabromobipheny1 mg/kg 六溴聯苯 / Hexabromobiphenyl 5 n. d. mg/kg 5 七溴聯苯 / Heptabromobiphenyl n. d. mg/kg 5 n. d. 八溴聯苯 / Octabromobiphenyl mg/kg 5 n. d. 九溴聯苯 / Nonabromobiphenyl mg/kg 参考IEC 62321-6: 2015方法, 以氣相 5 十溴聯苯 / Decabromobiphenyl 層析/質譜儀檢測. / With reference n. d. mg/kg 多溴聯苯醚總和 / Sum of PBDEs to IEC 62321-6: 2015 and performed n. d. mg/kg by GC/MS. 5 n. d. 一溴聯苯醚 / Monobromodiphenyl ether mg/kg 二溴聯苯醚 / Dibromodiphenyl ether 5 n. d. mg/kg 5 n. d. 三溴聯苯醚 / Tribromodiphenyl ether mg/kg 5 四溴聯苯醚 / Tetrabromodiphenyl ether n. d. mg/kg 5 五溴聯苯醚 / Pentabromodiphenyl ether n. d. mg/kg 5 六溴聯苯醚 / Hexabromodiphenyl ether n. d. mg/kg n. d. 5 七溴聯苯醚 / Heptabromodiphenyl ether mg/kg 5 n. d. 八溴聯苯醚 / Octabromodiphenyl ether mg/kg 九溴聯苯醚 / Nonabromodiphenyl ether mg/kg 5 n. d. 5 十溴聯苯醚 / Decabromodiphenyl ether n. d. mg/kg

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(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

(慶邦電子元器件 (泗洪) 有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

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備註(Note):

- 1. mg/kg = ppm; 0. 1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限值)
- 4. "-" = Not Regulated (無規格值)
- 5. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個別單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

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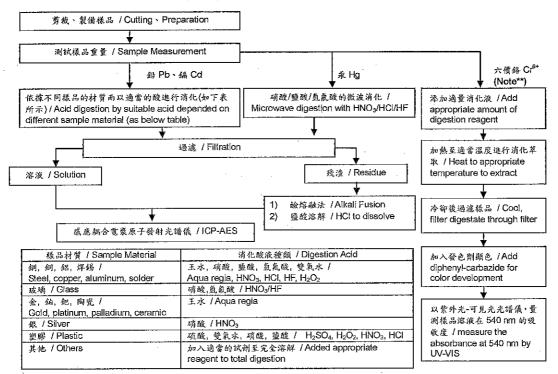
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根據以下的流程圖之條件,樣品已完全溶解。(六價絡測試方法除外)

These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)

- 测試人員:楊登偉 / Technician: Climbgreat Yang
- 测试負責人:張啟興 / Supervisor: Troy Chang



Note** (For IEC 62321)

(1) 針對非金屬材料加入鹼性消化液,加熱至 90~95℃萃取. / For non-metallic material, add alkaline digestion reagent and heat to 90~95℃.

(2) 針對金屬材料加入純水,加熱至沸腾萃取. / For metallic material, add pure water and heat to boiling.

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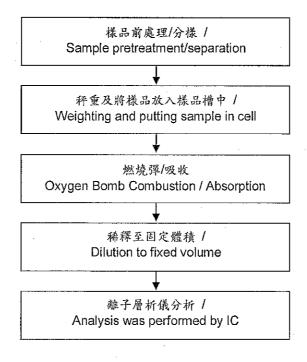
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鹵素分析流程圖 / Analytical flow chart of halogen content

- 測試人員:陳思臻 / Name of the person who made measurement: Rita Chen
- 測試負責人:張啟興 / Name of the person in charge of measurement: Troy Chang



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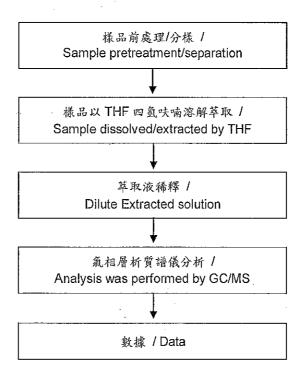
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可塑劑分析流程圖 / Analytical flow chart of phthalate content

- 測試人員:徐毓明 / Name of the person who made measurement: Andy Shu
- 測試負責人: 張啟興 / Name of the person in charge of measurement: Troy Chang

【測試方法/Test method: IEC 62321-8】



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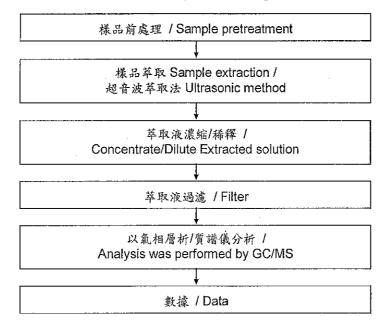
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六溴環十二烷分析流程圖 / HBCDD analytical flow chart

- 測試人員: 翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人: 張啟興 / Name of the person in charge of measurement: Troy Chang



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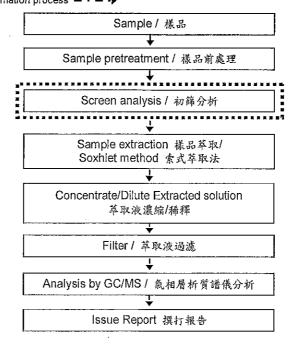
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多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員: 翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啟興 / Name of the person in charge of measurement: Troy Chang

初次測試程序 / First testing process -選擇性篩檢程序 / Optional screen process ==== 確認程序 / Confirmation process - · - →



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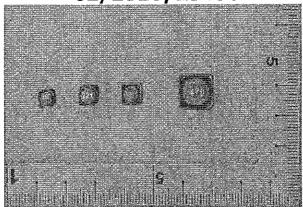
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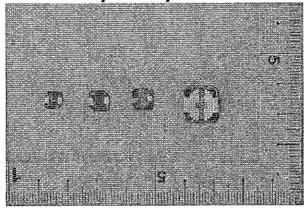
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* 照片中如有箭頭標示,則表示為實際檢測之樣品/部位. * (The tested sample / part is marked by an arrow if it's shown on the photo.)

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